

Notice of References Cited	Application/Control No. 10/526,059		Applicant(s)/Patent Under Reexamination ELLISON ET AL.	
	Examiner Nicole T. Gugliotta		Art Unit 4174	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,709,745	01-1998	Larkin et al.	117/96
*	B	US-6,180,958 B1	01-2001	Cooper, Jr., James Albert	257/77
*	C	US-5,043,773	08-1991	Precht et al.	257/77
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	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Kordina et al. "Long minority carrier lifetime in 6H SiC grown by chemical vapor deposition". Appl. Phys. Lett. 66 (2), 9 January 1995. pgs 189 - 191.
	V	Kordina et al. "The minority carrier lifetime of n-type 4H and 6H-SiC epitaxial layers". Appl. Phys. Lett. 69 (5), 29 July 1996. pgs 679 - 681.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.